

## **Notice of References Cited**

Application/Control No. <b>09/769,170</b>		Applicant(s)/Patent Under Reexam <b>Chu et al</b>	
Examiner <b>Edward Wojciechowicz</b>	Art Unit <b>2815</b>		Page 1 of 1

### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
X	A	5,856,229	1/1999	Sakaguchi et al	257	347
X	B	5,528,397	6/1996	Zavracky et al	257	347
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### FOREIGN PATENT DOCUMENTS

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	N					
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### NON-PATENT DOCUMENTS

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